

HB56D232B Series

2,097,152-Word x 32-Bit High Density Dynamic RAM Module

T-46-23-18

DESCRIPTION

The HB56D232B is a 2M x 32 dynamic RAM module, mounted 16 pieces of 4Mbit DRAM (HM514400JP) sealed in SOJ package. An outline of the HB56D232B is 72-pin single in-line package. Therefore, the HB56D232B makes high density mounting possible without surface mount technology. The HB56D232B provides common data inputs and outputs. Decoupling capacitors are mounted beneath each SOJ but only on the one side of its module board.

FEATURES

- 72-pin Single In-line Package
Lead Pitch 1.27mm
- Single 5V (±5%) Supply
- High Speed
Access Time 80 ns/100 ns/120 ns (max)
- Low Power Dissipation
Active Mode 3.99W/3.57W/3.15W (max)
Standby Mode 168 mW (max)
- Fast Page Mode Capability
- 1,024 Refresh Cycles (16 ms)
- 2 Variations of Refresh
RAS Only Refresh
CAS Before RAS Refresh
- TTL Compatible

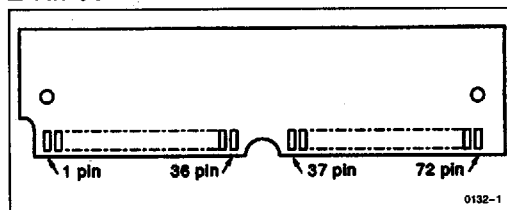
ORDERING INFORMATION

Part No.	Access Time	Package
HB56D232B-8	80 ns	72-pin SIP Socket Type
HB56D232B-10	100 ns	
HB56D232B-12	120 ns	

PRESENCE DETECT PINOUT

Pin No.	Pin Name	HB56D132BR		
		80 ns	100 ns	120 ns
67	PD ₁	V _{SS}	V _{SS}	V _{SS}
68	PD ₂	V _{SS}	V _{SS}	V _{SS}
69	PD ₃	NC	V _{SS}	NC
70	PD ₄	V _{SS}	V _{SS}	NC

PIN OUT

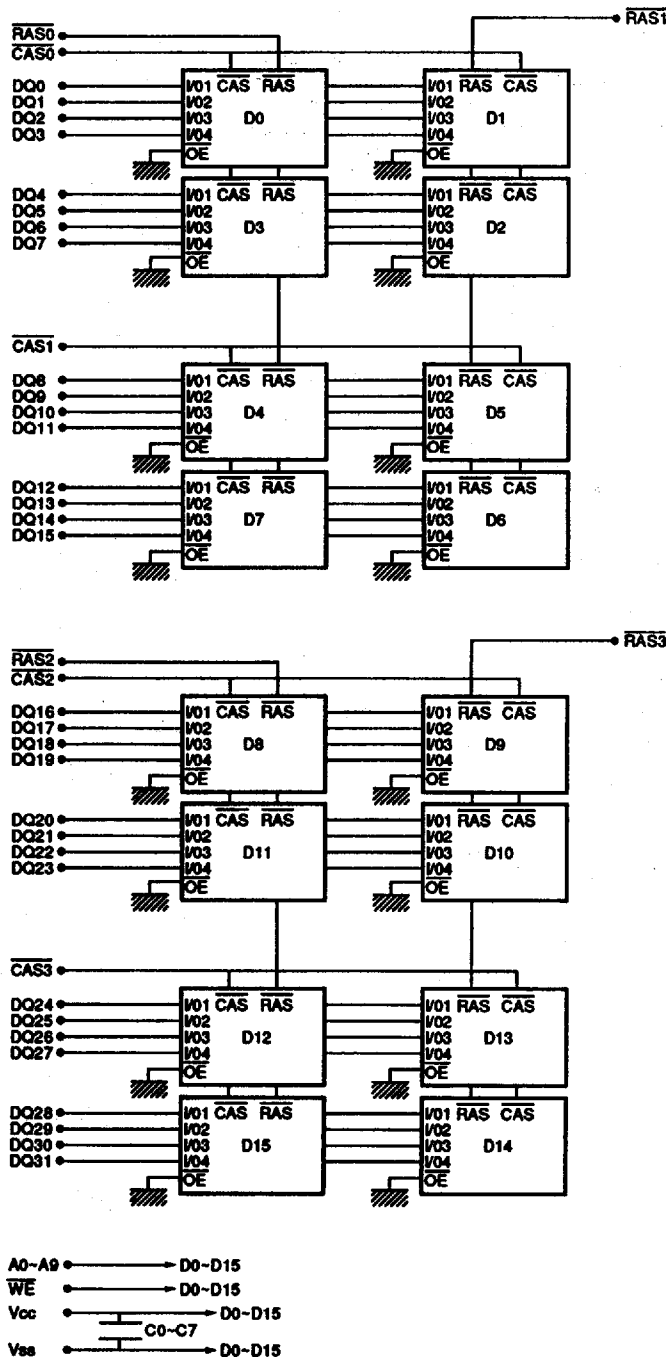


Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name
1	V _{SS}	19	NC	37	NC	55	DQ ₁₁
2	DQ ₀	20	DQ ₄	38	NC	56	DQ ₂₇
3	DQ ₁₆	21	DQ ₂₀	39	V _{SS}	57	DQ ₁₂
4	DQ ₁	22	DQ ₅	40	CAS ₀	58	DQ ₂₈
5	DQ ₁₇	23	DQ ₂₁	41	CAS ₂	59	V _{CC}
6	DQ ₂	24	DQ ₆	42	CAS ₃	60	DQ ₂₉
7	DQ ₁₈	25	DQ ₂₂	43	CAS ₁	61	DQ ₁₃
8	DQ ₃	26	DQ ₇	44	RAS ₀	62	DQ ₃₀
9	DQ ₁₉	27	DQ ₂₃	45	RAS ₁	63	DQ ₁₄
10	V _{CC}	28	A ₇	46	NC	64	DQ ₃₁
11	NC	29	NC	47	WE	65	DQ ₁₅
12	A ₀	30	V _{CC}	48	NC	66	NC
13	A ₁	31	A ₈	49	DQ ₈	67	PD ₁
14	A ₂	32	A ₉	50	DQ ₂₄	68	PD ₂
15	A ₃	33	RAS ₃	51	DQ ₉	69	PD ₃
16	A ₄	34	RAS ₂	52	DQ ₂₅	70	PD ₄
17	A ₅	35	NC	53	DQ ₁₀	71	NC
18	A ₆	36	NC	54	DQ ₂₆	72	V _{SS}

PIN DESCRIPTION

Pin Name	Function
A ₀ -A ₉	Address Input
A ₀ -A ₉	Refresh Address Input
DQ ₀ -DQ ₃₁	Data-in/Data-out
CAS ₀ -CAS ₃	Column Address Strobe
RAS ₀ -RAS ₃	Row Address Strobe
WE	Read/Write Enable
V _{CC}	Power Supply (+ 5V)
V _{SS}	Ground
PD ₁ -PD ₄	Presence Detect Pin
NC	Non-Connection





* D0-D15 : HM514400JP

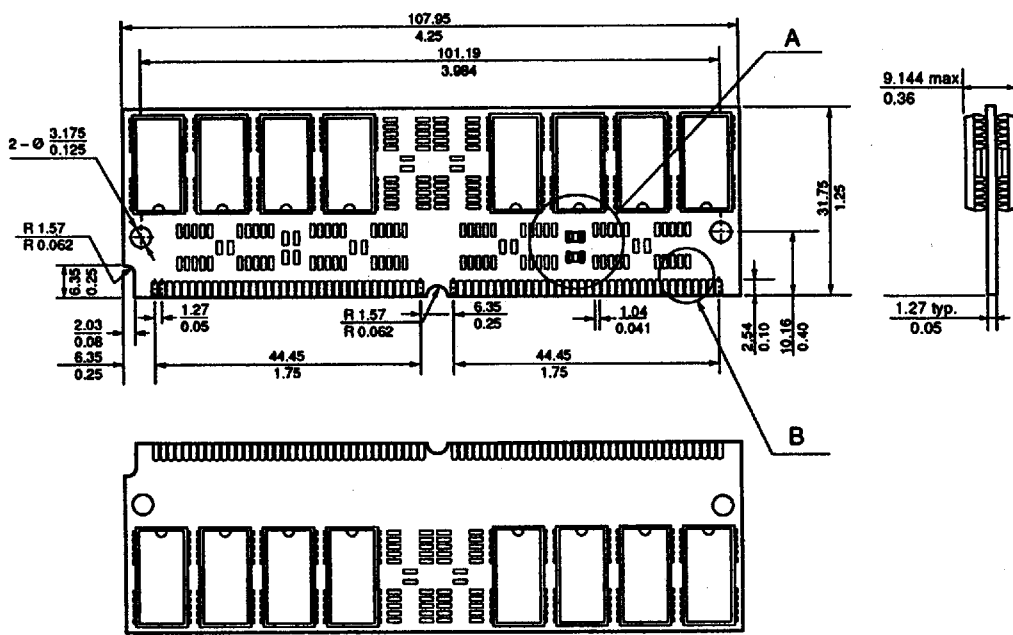
0132-2



■ PHYSICAL OUTLINE

T-46-23-18

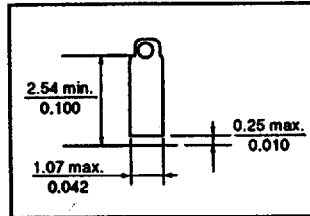
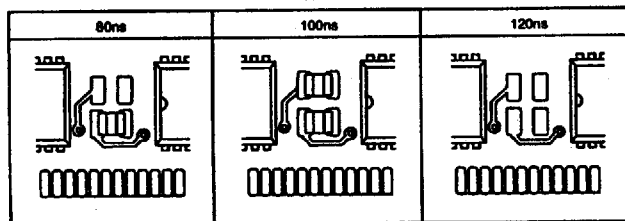
Unit: $\frac{\text{mm}}{\text{inch}}$



0132-3

Detail A

Detail B



0132-4

0132-5

Note: The plating of the contact finger is gold.



HB56D232B Series

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■ **ABSOLUTE MAXIMUM RATINGS**

Parameter	Symbol	Value	Unit	
Voltage on Any Pin Relative to V _{SS}	(Input)	V _{in}	- 1.0 to + 7.0	V
	(Output)	V _{out}	- 1.0 to + 7.0	V
Supply Voltage Relative to V _{SS}	V _{CC}	- 1.0 to + 7.0	V	
Short Circuit Output Current	I _{out}	50	mA	
Power Dissipation	P _T	8	W	
Operating Temperature	T _{opr}	0 to + 70	°C	
Storage Temperature	T _{stg}	- 55 to + 125	°C	

■ **ELECTRICAL CHARACTERISTICS**

• **Recommended DC Operating Conditions** (T_A = 0 to + 70°C)

Parameter	Symbol	Min	Typ	Max	Unit	Note
Supply Voltage	V _{SS}	0	0	0	V	
	V _{CC}	4.75	5.0	5.25	V	1
Input High Voltage	V _{IH}	2.4	—	5.5	V	1
Input Low Voltage	V _{IL}	- 1.0	—	0.8	V	1

Note: 1. All voltage referenced to V_{SS}.

• **DC Electrical Characteristics** (T_A = 0 to + 70°C, V_{CC} = 5V ± 5%, V_{SS} = 0V)

Parameter	Symbol	HB56D232B-8		HB56D232B-10		HB56D232B-12		Unit	Test Conditions	Note
		Min	Max	Min	Max	Min	Max			
Operating Current	I _{CC1}	—	760	—	680	—	600	mA	t _{RC} = Min	1, 2
Standby Current	I _{CC2}	—	32	—	32	—	32	mA	TTL Interface R _{AS} , C _{AS} = V _{IH} , D _{out} = High-Z	
		—	16	—	16	—	16	mA	CMOS Interface R _{AS} , C _{AS} ≥ V _{CC} - 0.2V, D _{out} = High-Z	
R _{AS} Only Refresh Current	I _{CC3}	—	760	—	680	—	600	mA	t _{RC} = Min	2
Standby Current	I _{CC5}	—	80	—	80	—	80	mA	R _{AS} = V _{IH} , C _{AS} = V _{IL} , D _{out} = Enable	1
C _{AS} Before R _{AS} Refresh Current	I _{CC6}	—	760	—	680	—	600	mA	t _{RC} = Min	
Page Mode Current	I _{CC7}	—	760	—	680	—	600	mA	t _{pC} = Min	1, 3
Input Leakage Current	I _{LI}	- 10	10	- 10	10	- 10	10	μA	0V ≤ V _{in} ≤ 7V	
Output Leakage Current	I _{LO}	- 10	10	- 10	10	- 10	10	μA	0V ≤ V _{out} ≤ 7V, D _{out} = Disable	
Output High Voltage	V _{OH}	2.4	V _{CC}	2.4	V _{CC}	2.4	V _{CC}	V	High I _{out} = - 5 mA	
Output Low Voltage	V _{OL}	0	0.4	0	0.4	0	0.4	V	Low I _{out} = 4.2 mA	

- Notes: 1. I_{CC} depends on output load condition when the device is selected, I_{CC} (max) is specified at the output open condition.
 2. Address can be changed less than three times while R_{AS} = V_{IL}.
 3. Address can be changed once or less while C_{AS} = V_{IH}.



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• Capacitance ($T_A = 25^\circ\text{C}$, $V_{CC} = 5V \pm 5\%$)

Parameter	Symbol	Typ	Max	Unit	Note
Input Capacitance (Address)	C_{I1}	—	121	pF	1
Input Capacitance (\overline{WE})	C_{I2}	—	137	pF	1
Input Capacitance (\overline{RAS} , \overline{CAS})	C_{I3}	—	48	pF	1
Output Capacitance (DQ_0 – DQ_{31})	$C_{I/O}$	—	29	pF	1, 2

- Notes: 1. Capacitance measured with Boonton Meter or effective capacitance measuring method.
 2. $\overline{CAS} = V_{IH}$ to disable D_{out} .

• AC Characteristics ($T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$, $V_{CC} = 5V \pm 5\%$, $V_{SS} = 0V$)^{1, 12}

Read, Write, and Refresh Cycles (Common Parameters)

Parameter	Symbol	HB56D232B-8		HB56D232B-10		HB56D232B-12		Unit	Note
		Min	Max	Min	Max	Min	Max		
Random Read or Write Cycle Time	t_{RC}	150	—	180	—	210	—	ns	
\overline{RAS} Precharge Time	t_{RP}	60	—	70	—	80	—	ns	
\overline{RAS} Pulse Width	t_{RAS}	80	10000	100	10000	120	10000	ns	
\overline{CAS} Pulse Width	t_{CAS}	25	10000	25	10000	30	10000	ns	
Row Address Setup Time	t_{ASR}	0	—	0	—	0	—	ns	
Row Address Hold Time	t_{RAH}	12	—	15	—	15	—	ns	
Column Address Setup Time	t_{ASC}	0	—	0	—	0	—	ns	
Column Address Hold Time	t_{CAH}	20	—	20	—	25	—	ns	
\overline{RAS} to \overline{CAS} Delay Time	t_{RCD}	22	55	25	75	25	90	ns	8
\overline{RAS} to Column Address Delay Time	t_{RAD}	17	40	20	55	20	65	ns	9
\overline{RAS} Hold Time	t_{RSH}	25	—	25	—	30	—	ns	
\overline{CAS} Hold Time	t_{CSH}	80	—	100	—	120	—	ns	
\overline{CAS} to \overline{RAS} Precharge Time	t_{CRP}	5	—	10	—	10	—	ns	
Transition Time (Rise and Fall)	t_T	3	50	3	50	3	50	ns	7
Refresh Period	t_{REF}	—	16	—	16	—	16	ms	15

Read Cycle

Parameter	Symbol	HB56D232B-8		HB56D232B-10		HB56D232B-12		Unit	Note
		Min	Max	Min	Max	Min	Max		
Access Time from \overline{RAS}	t_{RAC}	—	80	—	100	—	120	ns	2, 3
Access Time from \overline{CAS}	t_{CAC}	—	25	—	25	—	30	ns	3, 4
Access Time from Address	t_{AA}	—	40	—	45	—	55	ns	3, 5
Read Command Setup Time	t_{RCS}	0	—	0	—	0	—	ns	
Read Command Hold Time to \overline{CAS}	t_{RCH}	0	—	0	—	0	—	ns	
Read Command Hold Time to \overline{RAS}	t_{RRH}	10	—	10	—	10	—	ns	
Column Address to \overline{RAS} Lead Time	t_{RAL}	40	—	45	—	55	—	ns	
Output Buffer Turn-off Time	t_{OFF}	0	20	0	25	0	30	ns	6



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Write Cycle

Parameter	Symbol	HB56D232B-8		HB56D232B-10		HB56D232B-12		Unit	Note
		Min	Max	Min	Max	Min	Max		
Write Command Setup Time	t _{WCS}	0	—	0	—	0	—	ns	10
Write Command Hold Time	t _{WCH}	15	—	20	—	25	—	ns	
Write Command Pulse Width	t _{WP}	15	—	20	—	25	—	ns	
Data-in Setup Time	t _{DS}	0	—	0	—	0	—	ns	11
Data-in Hold Time	t _{DH}	15	—	20	—	25	—	ns	11

Refresh Cycle

Parameter	Symbol	HB56D232B-8		HB56D232B-10		HB56D232B-12		Unit	Note
		Min	Max	Min	Max	Min	Max		
CAS Setup Time (CAS Before RAS Refresh Cycle)	t _{CSR}	10	—	10	—	10	—	ns	
CAS Hold Time (CAS Before RAS Refresh Cycle)	t _{CHR}	20	—	20	—	25	—	ns	
RAS Precharge to CAS Hold Time	t _{RPC}	10	—	10	—	10	—	ns	

Fast Page Mode Cycle

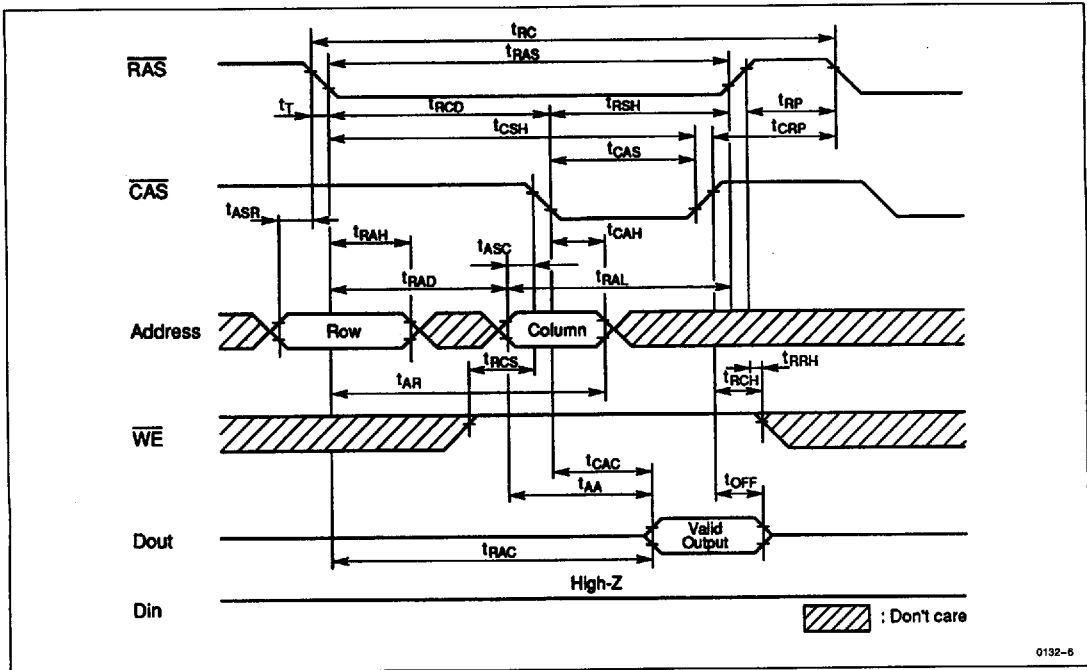
Parameter	Symbol	HB56D232B-8		HB56D232B-10		HB56D232B-12		Unit	Note
		Min	Max	Min	Max	Min	Max		
Fast Page Mode Cycle Time	t _{PC}	55	—	55	—	65	—	ns	
Fast Page Mode CAS Precharge Time	t _{CP}	10	—	10	—	15	—	ns	
Fast Page Mode RAS Pulse Width	t _{RASC}	80	100000	100	100000	120	100000	ns	13
Access Time from CAS Precharge	t _{ACP}	—	50	—	50	—	60	ns	14
RAS Hold Time from CAS Precharge	t _{RHCP}	50	—	50	—	50	—	ns	

- Notes:
1. AC measurements assume t_T = 5 ns.
 2. Assumes that t_{RCD} ≤ t_{RCD} (max) and t_{RAD} ≤ t_{RAD} (max). If t_{RCD} or t_{RAD} is greater than the maximum recommended value shown in this table, t_{RAC} exceeds the value shown.
 3. Measured with a load circuit equivalent to 2 TTL loads and 100 pF.
 4. Assumes that t_{RCD} ≥ t_{RCD} (max) and t_{RAD} ≤ t_{RAD} (max).
 5. Assumes that t_{RCD} ≤ t_{RCD} (max) and t_{RAD} ≥ t_{RAD} (max).
 6. t_{OFF} (max) is defined as the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.
 7. V_{IH} (min) and V_{IL} (max) are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL}.
 8. Operation with the t_{RCD} (max) limit insures that t_{RAC} (max) can be met, t_{RCD} (max) is specified as a reference point only, if t_{RCD} is greater than the specified t_{RCD} (max) limit, then access time is controlled exclusively by t_{CAC}.
 9. Operation with the t_{RAD} (max) limit insures that t_{RAC} (max) can be met, t_{RAD} (max) is specified as a reference point only, if t_{RAD} is greater than the specified t_{RAD} (max) limit, then access time is controlled exclusively by t_{AA}.
 10. Early write cycle only (t_{WCS} ≥ t_{WCS} (min)).
 11. These parameters are referenced to CAS leading edge in an early write cycle.
 12. An initial pause of 100 μs is required after power up followed by a minimum of eight initialization cycles (any combination of cycles containing RAS clock such as RAS only refresh).
 13. t_{RASC} is determined by RAS pulse width in fast page mode cycles.
 14. Access time is determined by the longer of t_{AA} or t_{CAC} or t_{ACP}.
 15. t_{REF} is determined by 1,024 refresh cycles.



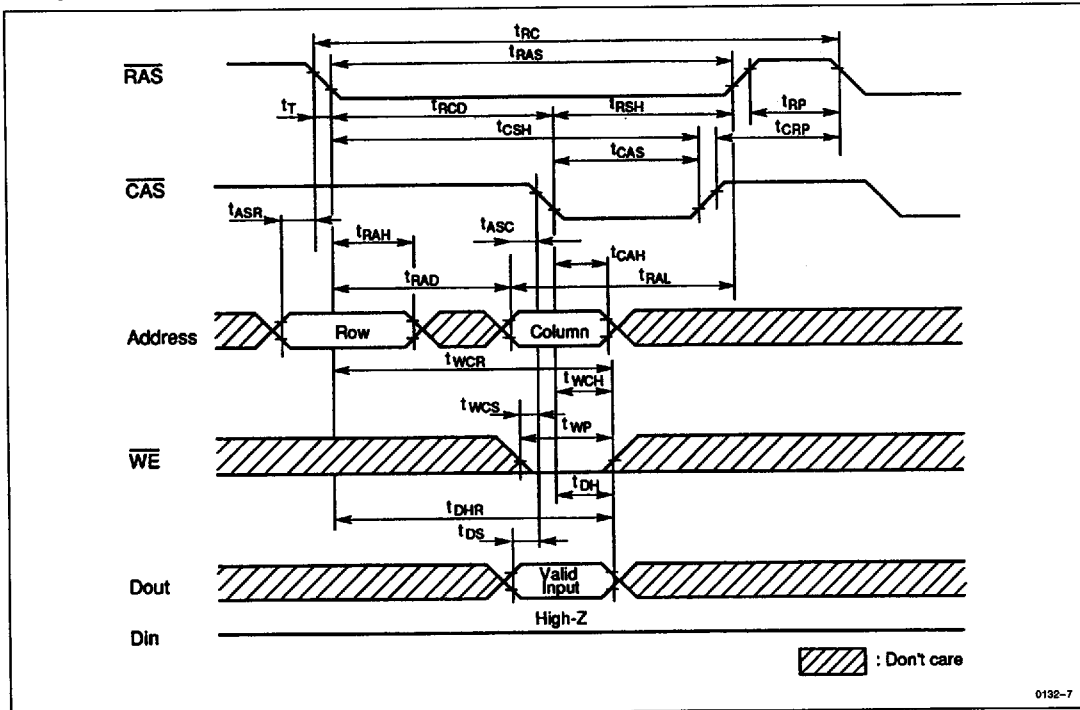
■ TIMING WAVEFORMS

• Read Cycle



0132-6

• Early Write Cycle

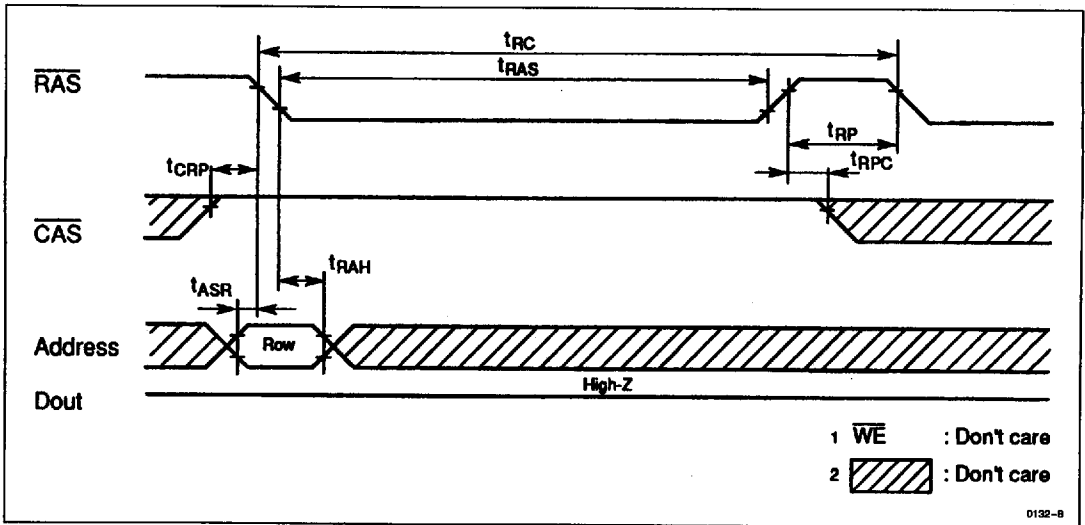


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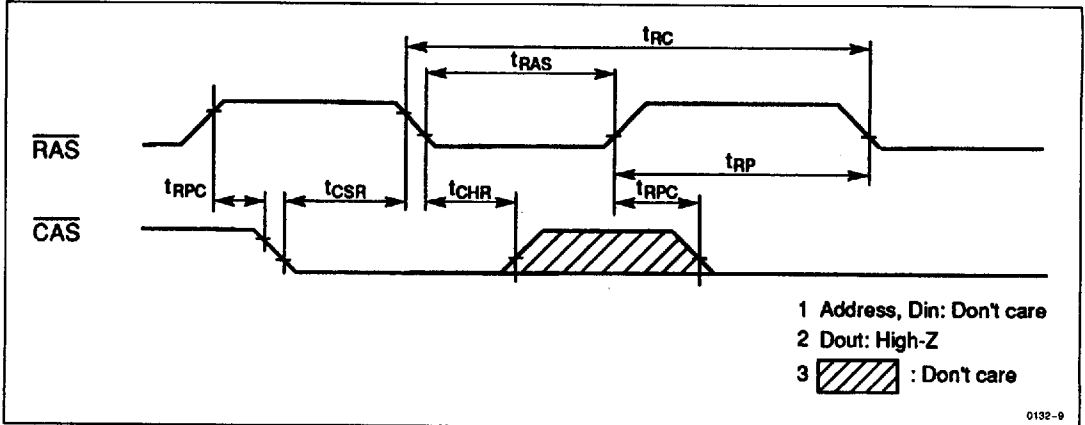


• RAS Only Refresh Cycle

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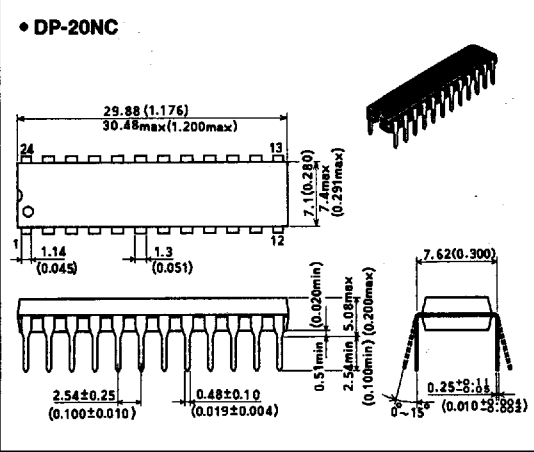
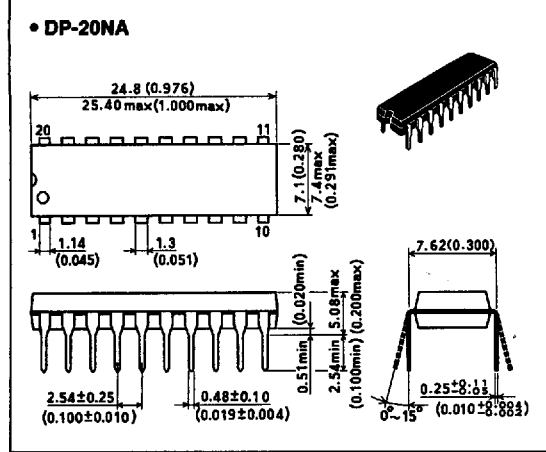
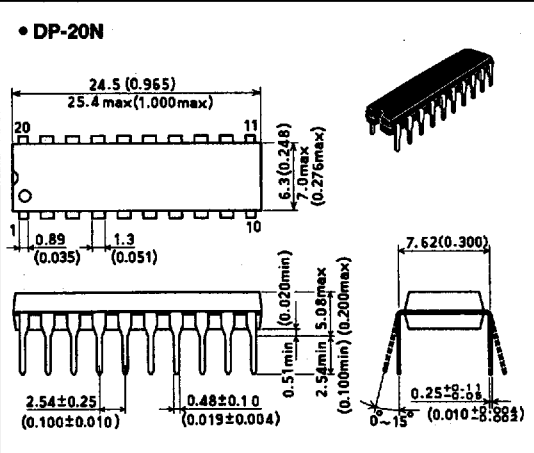
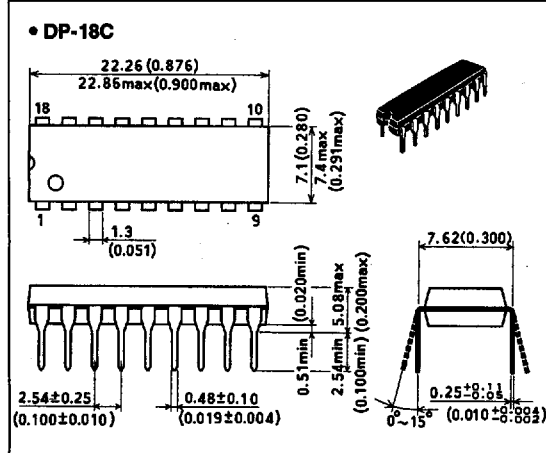
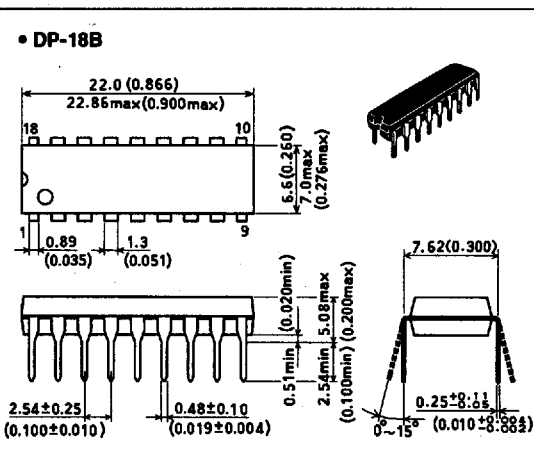
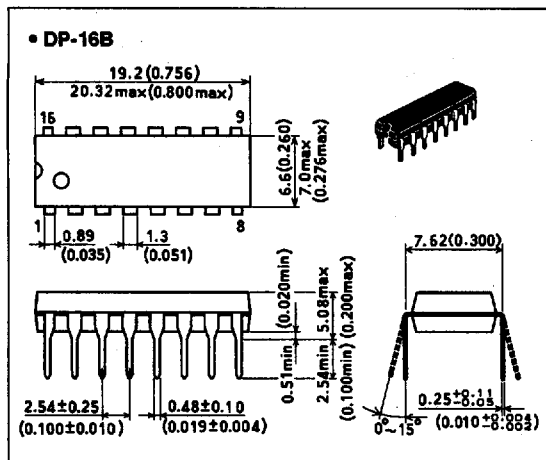
• CAS Before RAS Refresh Cycle



T-90-20

Unit: mm (inch) Scale 3/2

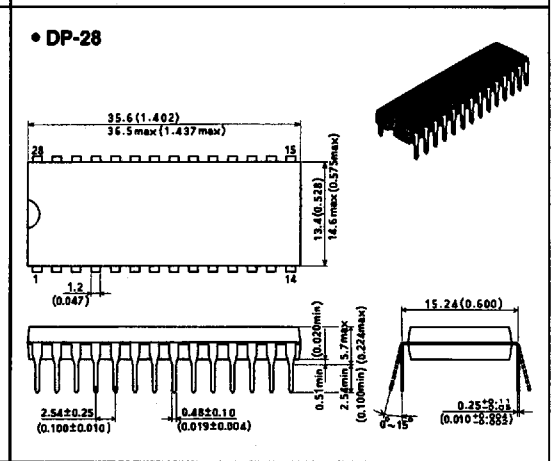
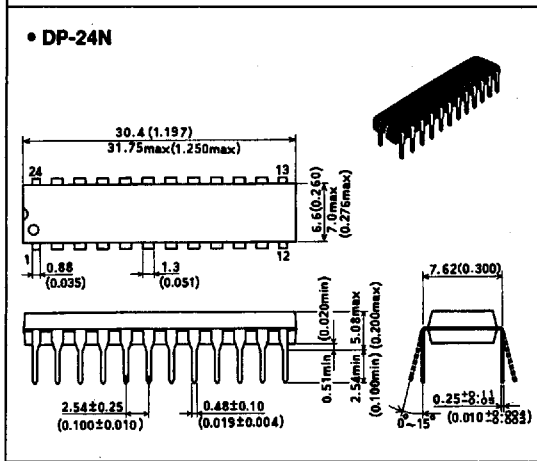
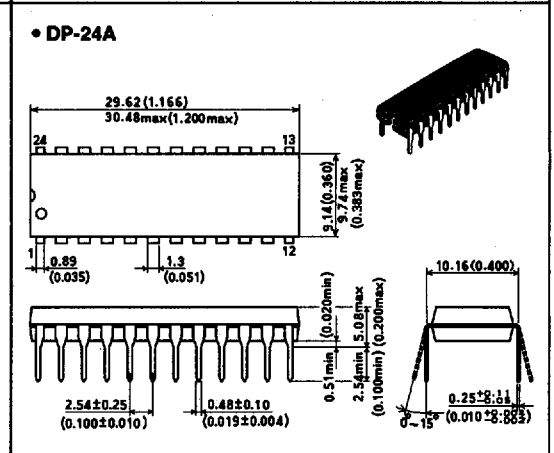
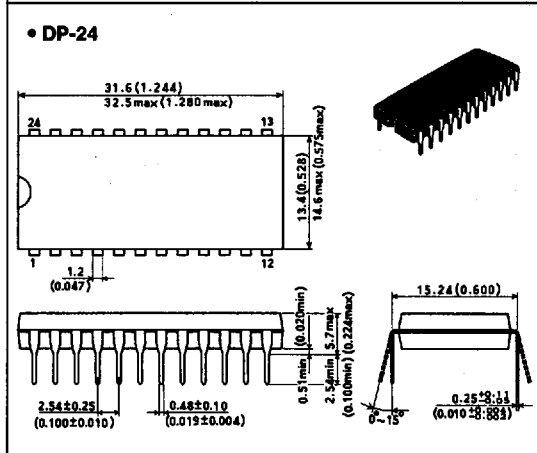
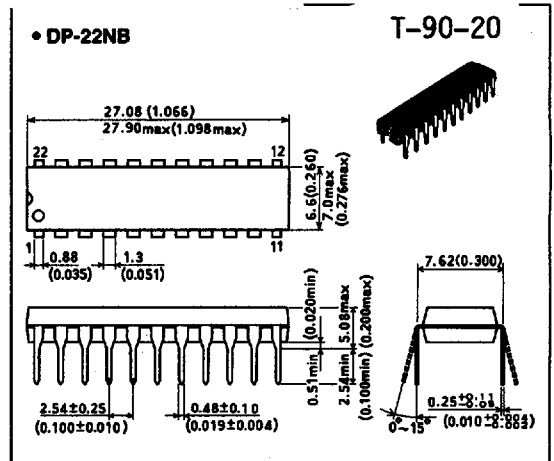
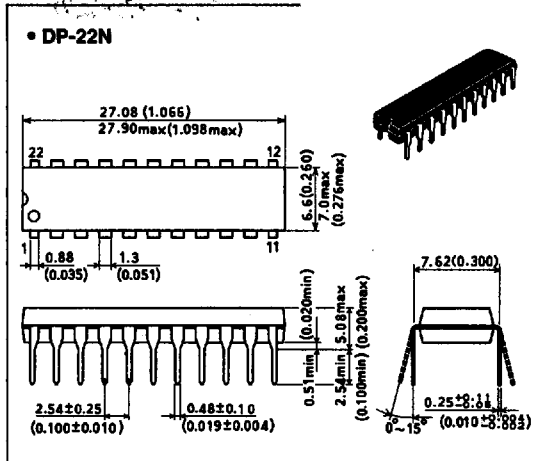
• Dual-in-line Plastic



• Dual-in-line Plastic

HITACHI/ LOGIC/ARRAYS/MEM

Unit: mm (inch) Scale 3/2



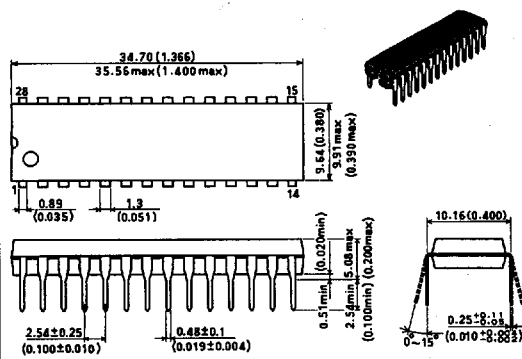
• Dual-in-line Plastic

HITACHI/ LOGIC/ARRAYS/MEM

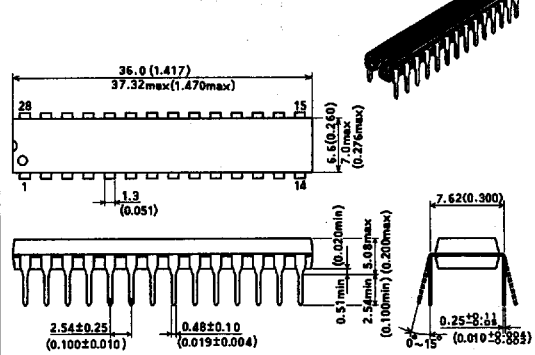
Unit: mm (inch) Scale 3/2

T-90-20

• DP-28C



• DP-28N

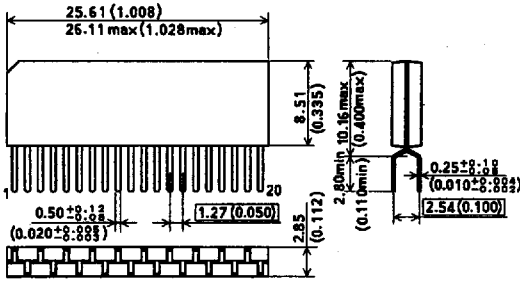
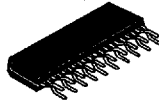


• Zigzag-in-line Plastic

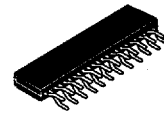
HITACHI/ LOGIC/ARRAYS/MEM

Unit: mm (inch) Scale 3/2

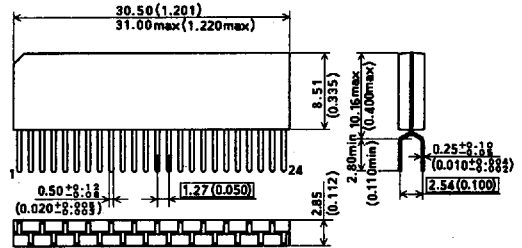
• ZP-20



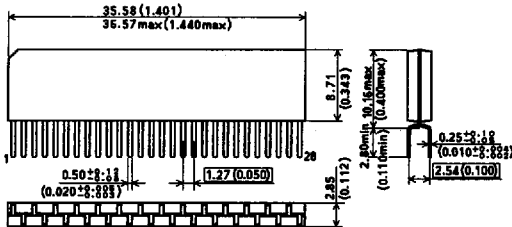
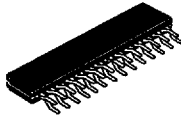
• ZP-24



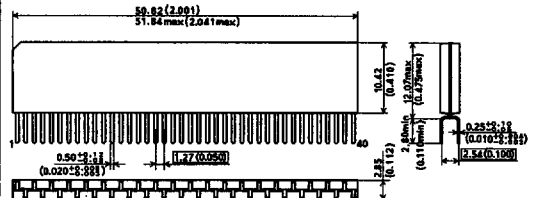
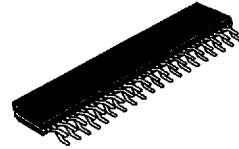
T-90-20



• ZP-28



• ZP-40



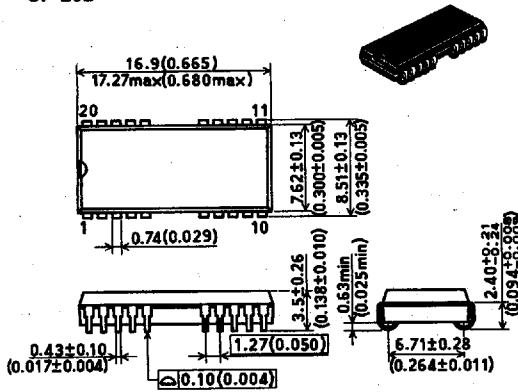
• Flat Package (J-bend Leads)

HITACHI/ LOGIC/ARRAYS/MEM

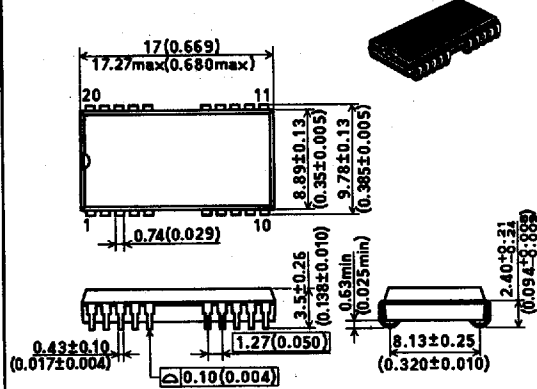
Unit: mm (inch) Scale 3/2

T-90-20

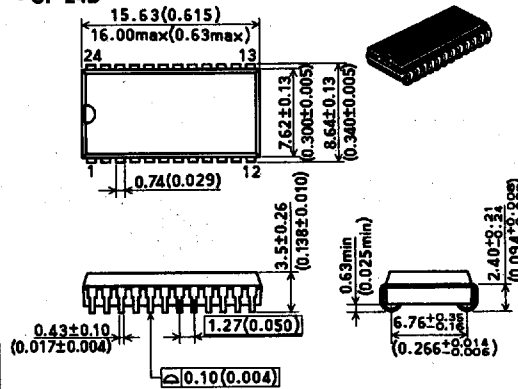
• CP-20D



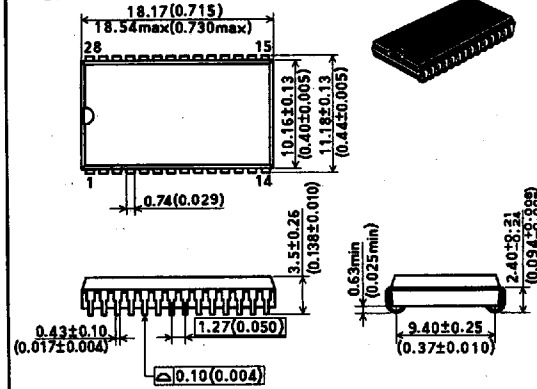
• CP-20DA



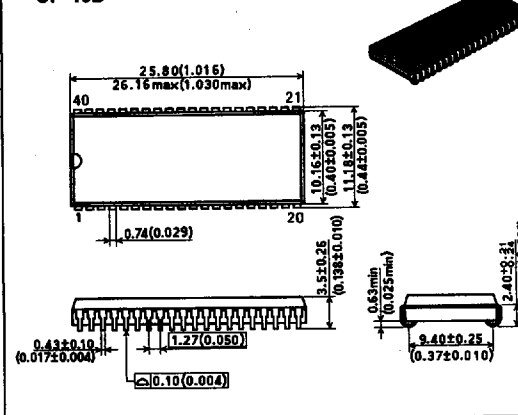
• CP-24D



• CP-28D

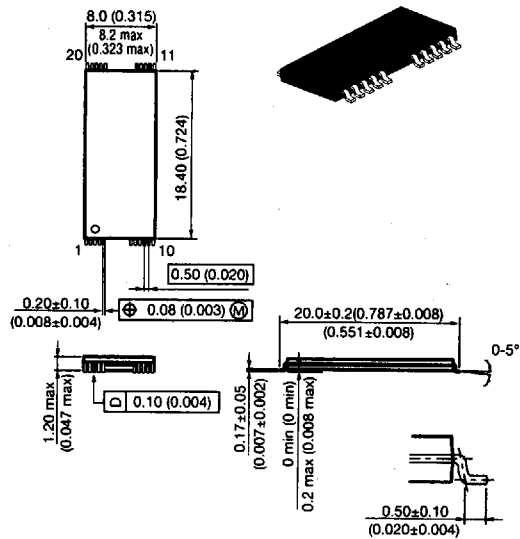


• CP-40D



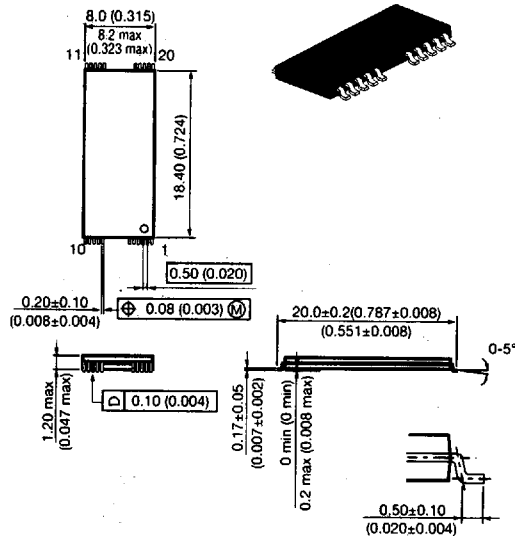
• TSOP (Thin Small Outline Packag^e) HITACHI/ LOGIC/ARRAYS/MEM Unit: mm (inch) Scale 3/2

• TFP-20DA

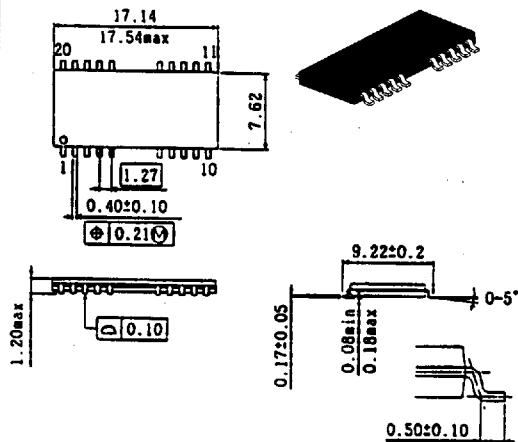


• TFP-20DAR

T-90-20



• TTP-20D



• TTP-20DR

